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SHEET 1 OF 5

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 211147US99	SHEET 1 OF 5		SERIAL NO. 09/903,784
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Aroon V. TUNGARE, et al.					
		FILING DATE July 13, 2001		GROUP 2826			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
RE	UT	5,528,209	06/18/96	Macdonald et al.			
	UV	5,998,781	12/07/99	Vawter et al.			
	UW	6,110,813	08/29/00	Ota et al.			
	UX	6,452,232 B1	09/17/02	Adan			
	UY	6,049,110	04/11/00	Koh			
	UZ	5,559,368	09/24/96	Hu et al.			
	VA	6,392,253 B1	05/21/02	Saxena			
	VB	5,585,288	12/17/96	Davis et al.			
	VC	5,268,327	12/07/93	Vernon			
	VD	6,198,119 B1	03/06/01	Nabatame et al.			
	VE	6,113,225	09/05/00	Miyata et al.			
	VF	5,262,659	11/16/93	Grudkowski et al.			
	VG	6,239,012 B1	05/29/01	Kinsman			
	VH	6,297,598	10/02/01	Wang et al.			
	VI	2002/140012	10/03/02	Droopad			
	VJ	4,866,489	09/12/89	Yokogawa et al.			
	VK	6,080,378	06/27/00	Yokota et al.			
	VL	5,508,554	04/16/96	Takatani et al.			
	VM	6,477,285 B1	11/05/02	Shanley			
	VN	4,695,120	09/22/87	Holder			
	VO	5,882,948	03/16/99	Jewell			
	VP	5,574,589	11/12/96	Feuer et al.			
	VQ	5,510,665	04/23/96	Conley			
	VR	4,804,866	02/14/89	Akiyama			
	VS	5,057,694	10/15/91	Idaka et al.			
	VT	5,635,453	06/03/97	Pique et al.			
	VU	5,719,417	02/17/98	Roeder et al.			
	VW	5,998,819	12/07/99	Yokoyama et al.			
Examiner <i>PM</i> Date Considered <i>08/10/03</i>							

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SHEET 2 OF 5

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 211147US99	SERIAL NO. 09/903,784		
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	VW	2002/0079576	06/27/02	Seshan			
	VX	5,148,504	09/15/92	Levi et al.			
	VY	2002/0195610 A1	12/26/02	Klosowiak			
	VZ	5,477,363	12/19/95	Matsuda			
	WA	5,905,571	05/18/99	Butler et al.			
	WB	5,570,226	10/29/96	Ota			
	WC	5,087,829	02/11/92	Ishibashi et al.			
	WD	2001/0020278 A1	09/06/01	Saito			
	WE	6,496,469 B1	12/17/02	Uchizaki			
	WF	5,679,947	10/21/97	Doi et al.			
	WG	2001/0036142 A1	11/01/01	Kadowaki et al.			
	WH	5,446,719	08/29/95	Yoshida et al.			
	WI	5,831,960	11/03/98	Jiang et al.			
	WJ	5,693,140	12/02/97	McKee et al.			
	WK	6,376,337 B1	04/23/02	Wang et al.			
	WL	4,177,094	12/04/79	Kroon			
	WM	5,216,359	06/01/93	Makki et al.			
	WN	6,307,996 B1	10/23/01	Nashimoto et al.			
	WO	5,371,621	12/06/94	Stevens			
	WP	2002/0145168 A1	10/10/02	Bojarczuk, Jr et al.			
	WQ	3,617,951	11/02/71	Anderson			
	WR	5,838,053	11/17/98	Bevan et al.			
	WS	5,684,302	11/04/97	Wersing et al.			
	WT	5,959,308	09/28/99	Shichijo et al.			
	WU	5,362,972	11/08/94	Yazawa et al.			
	WV	5,864,171	01/26/99	Yamamoto et al.			
	WW	5,028,563	07/02/91	Feit et al.			
	WX	5,937,115	08/10/99	Domash			
Examiner <i>John A. Tungare</i>					Date Considered <i>5/12/2003</i>		

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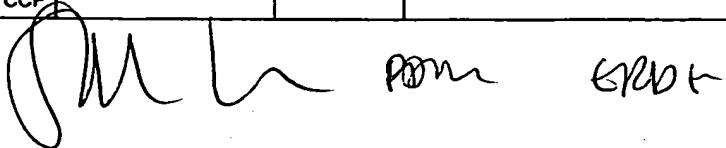
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LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Aroon V. TUNGARE, et al.					
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WY		5,878,175	03/02/99	Sonoda et al.			
		WZ 4,801,184	01/31/89	Revelli			
		XA 5,140,387	08/18/92	Okazaki et al.			
		XB 5,410,622	04/25/95	Okada et al.			
		XC 6,064,783	05/16/00	Congdon et al.			
		XD 5,772,758	06/30/98	Collins et al.			
		XE 5,666,376	09/09/97	Cheng			
		XF 5,976,953	11/02/99	Zavacky et al.			
		XG 5,578,162	11/26/96	D'Asaro et al.			
		XH 5,585,167	12/17/96	Satoh et al.			
		XI 5,674,813	10/07/97	Nakamura et al.			
		XJ 5,574,296	11/12/96	Park et al.			
		XK 6,504,189	01/07/03	Matsuda et al.			
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Examiner	Aroon V. TUNGARE				Date Considered	09/16/03	

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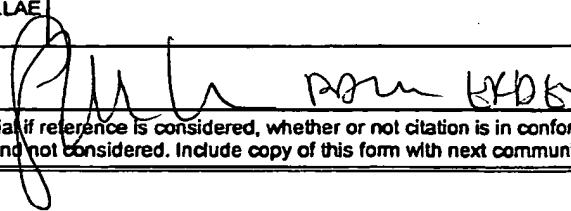


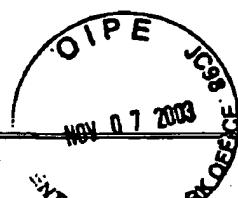
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D1	CBC	EP 1 035 769	09/13/00	Europe	
	CBD	EP 0 860 913	08/26/95	EUROPE	
	CBE	5-232307	09/10/93	JAPAN W/ENGLISH ABSTRACT	
	CBF	5-243525	09/31/93	JAPAN W/ENGLISH ABSTRACT	
	CBG	3-171617	07/25/91	JAPAN W/ENGLISH ABSTRACT	
	CBH	EP 1 089 338	04/04/01	EUROPE	
	CBI	01 294594	11/28/99	JAPAN (ABSTRACT)	
	CBJ	05 221800	08/31/93	JAPAN (ABSTRACT)	
	CBK	03-149882	11/07/89	JAPAN	
	CBL	0 614 256	09/07/94	EUROPE	
	CBM	1 054 442	11/22/00	EUROPE	
	CBN	0 852 416	07/08/98	EUROPE	
	CBO	W0 02/08806	01/31/02	WIPO	
	CBP	W0 01/59837	08/16/01	WIPO	
	CBQ	62-245205	10/26/87	JAPAN W/ENGLISH ABSTRACT	
	CBR	0 600 658	06/08/94	EUROPE	
	CBS	0 412 002	02/06/91	EUROPE	
	CBT	2000-349278	12/15/00	JAPAN (ENGLISH ABSTRACT)	
	CBU	01-196809	08/08/89	JAPAN (ENGLISH ABSTRACT)	
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	CBW	0 661 561	07/05/95	EUROPE	
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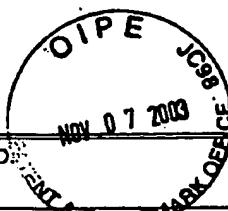
SHEET 5 OF 5

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 211147US99	SERIAL NO. 09/903,784
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Aroon V. TUNGARE, et al.		
		FILING DATE July 13, 2001	GROUP 2826	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)				
PK	KKAO	Charles Kittel: "Introduction to Solid State Physics": John Wiley & Sons, Inc. Fifth Edition; pp. 415		
	KKAP	Chyuan-Wei Chen et al: "Liquid-phase epitaxial growth and characterization of InGaAsP layers grown on GaAsP substrates for application to orange light-emitting diodes"; 931 Journal of Applied Physics; 77 (1995) 15 January, No. 2; Woodbury, NY, US; pp. 905-909		
	KKAQ	W. Zhu et al.: "Oriented diamond films grown on nickel substrates"; 320 Applied Physics Letters; 63(1993) September, No. 12, Woodbury, NY, US; pp. 1640-1642		
	KKAR	M. Schreck et al.: "Diamond/Ir/SrTiO ₃ : A material combination for improved heteroepitaxial diamond films"; Applied Physics Letters; Vol. 74, No. 5; February 1, 1999; pp. 650-652		
	KKAS	Yoshihiro Yokota et al.: "Cathodoluminescence of boron-doped heteroepitaxial diamond films on platinum"; Diamond and Related Materials 8(1999); pp. 1587-1591		
	KKAT	J. R. Busch et al.: "LINEAR ELECTRO-OPTIC RESPONSE IN SOL-GEL PZT PLANAR WAVEGUIDE"; Electronics Letters; 13th August 1992; Vol. 28, No. 17; pp. 1591-1592		
	KKAU	R. Droopad et al: "Epitaxial Oxide Films on Silicon: Growth, Modeling and Device Properties"; Mat. Res. Soc. Symp. Proc. Vol. 619; 2000 Materials Research Society; pp. 155-165		
	KKAV	H. Ohkubo et al.: "Fabrication of High Quality Perovskite Oxide Films by Lateral Epitaxy Verified with RHEED Oscillation"; 2419A Int. Conf. on Solid State Devices & Materials, Tsukuba, August 26-28 (1992); pp. 457-459		
	KKAW	Lin Li: "Ferroelectric/Superconductor Heterostructures"; Materials Science and Engineering; 29 (2000) pp. 153-181		
	KKAX	L. Fan et al.: "Dynamic Beam Switching of Vertical-Cavity Surface-Emitting Lasers with Integrated Optical Beam Routers"; IEEE Photonics Technology Letters; Vol. 9, No. 4; April 4, 1997; pp. 505-507		
	KKAY	Y. Q. Xu, et al.: "(Mn, Sb) doped-Pb(Zr,Ti)O ₃ infrared detector arrays"; Journal of Applied Physics; Vol. 88, No. 2; 15 July 2000; pp. 1004-1007		
↓	KKAZ	Kiyoko Kato et al.: "Reduction of dislocations in InGaAs layer on GaAs using epitaxial lateral overgrowth"; 2300 Journal of Crystal Growth 115 (1991) pp. 174-179; December 1991		
	LLAA	RECEIVED MAY 12 2003 TECHNOLOGY CENTER 2 DOC		
	LLAB			
	LLAC			
	LLAD			
	LLAE			
Examiner 		Date Considered 05/10/03		
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
FE	XN	6,233,435 B1	05/15/01	WONG				
	XO	4,723,321	02/02/88	SALEH				
	XP	6,181,920 B1	01/30/01	DENT ET AL				
	XQ	6,415,140 B1	07/02/02	BENJAMIN ET AL				
	XR	5,760,740	06/02/98	BLODGETT				
	XS	5,238,877	08/24/93	RUSSELL				
	XT	4,876,218	10/24/89	PESSA ET AL				
	XU	6,232,242 B1	05/15/01	HATA ET AL				
	XV	4,378,259	03/29/83	HASEGAWA ET AL				
	XW	6,278,541 B1	08/21/01	BAKER				
	XY	4,298,247	11/03/81	MICHELET ET AL				
	XZ	4,174,504	11/13/79	CHENAUSKY ET AL				
	YA	3,758,199	09/11/73	THAXTER				
	YB	6,362,558 B1	03/26/02	FUKUI				
	YC	6,140,746	10/31/00	MIYASHITA ET AL				
	YD	2002/0076878 A1	06/20/02	WASA ET AL				
	YE	6,419,849 B1	07/16/02	QIU ET AL				
	YF	2002/0179000 A1	12/05/02	LEE ET AL				
	YG	6,341,851	01/29/02	TAKAYAMA ET AL				
	YH	2001/0055820 A1	12/27/01	SAKURAI ET AL				
	YI	6,204,525 B1	03/20/01	SAKURAI ET AL				
	YJ	5,985,404	11/16/99	YANO ET AL				
	YK	6,538,359 B1	03/25/03	HIRAKU ET AL				
	YL	6,498,358 B1	12/24/02	LACH ET AL				
	YM	5,387,811	02/07/95	SAIGOH				
	YN	5,523,602	06/04/96	HORIUCHI ET AL				
	YO	5,362,998	11/08/94	IWAMURA ET AL				
↓	YP	5,188,976	02/23/93	KUME ET AL				
Examiner <i>John P. Murphy</i>					Date Considered <i>07/13/05</i>			

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SHEET 2 OF 4

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Re	YQ	6,501,121 B1	12/31/02	YU ET AL			
	YR	5,919,515	07/06/99	YANO ET AL			
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	YU	5,997,638	12/07/99	COPEL ET AL			
	YV	6,291,866	09/18/01	WALLACE			
	YW	5,365,477	11/15/94	COOPER, JR ET AL			
	YX	5,548,141	08/20/96	MORRIS ET AL			
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	ZD	5,919,522	07/06/99	BAUM ET AL			
	ZE	4,843,609	06/27/89	OHYA ET AL			
	ZF	4,626,878	12/02/86	KUWANO ET AL			
	ZG	4,525,871	06/25/85	FOYT ET AL			
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	ZI	6,059,895	05/09/00	CHU ET AL			
	ZJ	4,447,116	05/08/84	KING ET AL			
	ZK	6,022,671	02/08/00	BINKLEY ET AL			
	ZL	5,754,714	05/19/98	SUZUKI ET AL			
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	CCA	5-238894	09/17/93	JAPAN W/ENGLISH ABSTRACT	
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SHEET 4 OF 4

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		FILING DATE July 13, 2001	GROUP 2826	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)				
PG	LLAA	Peter Weiss; "Speed demon gets hooked on silicon"; Science News Online; Sept. 15, 2001; pp. 1-3		
	LLAB	"Motorola Develops New Super-Fast Chip"; USA Today; Sept. 4, 2001		
	LLAC	Lori Valigra; "Motorola Lays GaAs on Si Wafer"; AsiaBizTech; Nov. 2001 pp. 1-3		
	LLAD	"Holy Graail Motorola Claims High-Yield GaAs Breakthrough"; Micromagazine.com (no date available); pp. 1-3		
	LLAE	Jong-Gul YOON; "Growth of Ferroelectric LiNbO ₃ Thin Film on MgO-Buffered Si by the Sol-Gel Method"; Journal of the Korean Physical Society (Proc. Suppl.); Vol. 29, Nov. 1996; pp. S648-S651		
	LLAF	V. Bormand et al.; "Deposition of LiTaO ₃ thin films by pyrosol process"; Thin Solid Films 304 (1997); pp.239-244		
	LLAG	R. Droopad et al.; "Development of high dielectric constant epitaxial oxides on silicon by molecular beam epitaxy"; Materials Science and Engineering B87 (2001); pp.292-296		
	LLAH	A.K. Sharma et al.; "Integration of Pb(Zr0.52Ti0.48)O ₃ epiayers with Si by domain epitaxy"; Applied Physics Letters, Vol. 76, No. 11; March 13, 2000; pp. 1458-1460		
	LLAI	Dwight C. Streit et al; "High Reliability GaAs-AlGaAs HBT's by MBE with Be Base Doping and InGaAs Emitter Contacts"; 8179 Ieee Electron Device Letters; 12(1991) September, No. 9, New York, US		
	LLAJ	C. Y. Hung et al; "Piezoelectrically induced stress tuning of electro-optic devices"; 320 Applied Physics Letters; 59(1991) 30 December, No. 27, New York, US		
	LLAK	J. Piprek; "Heat Flow Analysis of Long-Wavelength VCSELs with Various DBR Materials"; University of Delaware, Materials Science, Newark, DE, 19716-3106; Oct. 31, 1994; pp. 286-287		
	LLAL	P. Mackowiak et al.; "Some aspects of designing an efficient nitride VCSEL resonator"; J. Phys. D: Appl. Phys. 34(2001); pp. 954-958		
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Examiner <i>Ram Tungare</i>		Date Considered 08/13/06		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.				